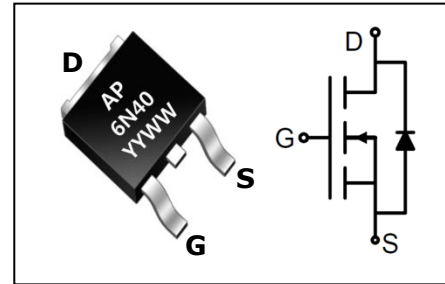


400V 6A Low Qg N-Ch Power MOSFET

FEATURES

- Low drain-source On resistance : $R_{DS(on)} = 0.9\Omega$ (Typ.)
- Low gate charge : $Q_g = 14nC$ (Typ.)
- Low reverse transfer capacitance : $C_{rss} = 9.5pF$ (Typ.)
- RoHS compliant device
- 100% avalanche tested



APPLICATIONS

- High speed switching
- LED power
- Motor power

Ordering Information

Part No	Package	Packing	Finish	Halogen	Packing Unit
AM6N40RD	TO-252	Reel & Tape	Sn	Free	2,500ea

Marking Information



- Row 1 : AP
- Row 2 : Product Information
- Row 3 : Date Code
 - YY : Year Code
 - WW : Week Code

Maximum Ratings ($T_c=25^\circ C$, unless otherwise noted)

Characteristic	Symbol	Rating	Unit
Drain-source voltage	V_{DS}	400	V
Gate-source voltage	V_{GS}	± 30	V
Drain current (DC)*	I_D	$T_c = 25^\circ C$	5.5
		$T_c = 100^\circ C$	3.46
Drain current (Pulsed)*	I_{DM}	22	A
Single avalanche energy ^(Note 2)	EAS	380	mJ
Repetitive avalanche current ^(Note 1)	I_{AR}	5.5	A
Repetitive avalanche energy ^(Note 1)	EAR	5.5	mJ
Power dissipation	P_D	55	W
Junction temperature	T_J	150	$^\circ C$
Storage temperature range	T_{stg}	-55~150	$^\circ C$

*Limited only maximum junction temperature

Thermal Characteristic

Characteristic	Symbol	Rating	Unit
Thermal resistance, junction to case	$R_{th(j-c)}$	Max. 2.27	°C/W
Thermal resistance, junction to ambient	$R_{th(j-a)}$	Max. 62.5	

Electrical Characteristics ($T_C=25\text{ }^\circ\text{C}$, unless otherwise noted)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	BV_{DSS}	$I_D = 250\mu\text{A}, V_{GS} = 0$	400	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$I_D = 250\mu\text{A}, V_{DS} = V_{GS}$	2	-	4	V
Drain-source cut-off current	I_{DSS}	$V_{DS} = 400\text{V}, V_{GS} = 0\text{V}$	-	-	1	μA
		$V_{DS} = 400\text{V}, T_C = 150^\circ\text{C}$	-	-	100	μA
Gate leakage current	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 30\text{V}$	-	-	± 100	nA
Drain-source on-resistance	$R_{DS(ON)}$	$V_{GS} = 10\text{V}, I_D = 2.75\text{A}$	-	0.9	1.05	Ω
Forward transfer conductance (Note 3)	g_{fs}	$V_{DS} = 10\text{V}, I_D = 2.75\text{A}$	-	4.4	-	S
Input capacitance	C_{iss}	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V},$ $f = 1.0\text{MHz}$	-	802	-	μF
Output capacitance	C_{oss}		-	65	-	
Reverse transfer capacitance	C_{rss}		-	9.5	-	
Turn-on delay time (Note 3,4)	$T_{d(on)}$	$V_{DS} = 220\text{V}, I_D = 5.5\text{A},$ $R_G = 25\Omega$	-	58	-	ns
Rise time (Note 3,4)	T_r		-	38	-	
Turn-off delay time (Note 3,4)	$t_{d(off)}$		-	95	-	
Fall time (Note 3,4)	t_f		-	30	-	
Total gate charge (Note 3,4)	Q_g	$V_{DS} = 320\text{V}, V_{GS} = 10\text{V}$ $I_D = 5.5\text{A}$	-	14	20	nC
Gate-source charge (Note 3,4)	Q_{gs}		-	4.7	-	
Gate-drain charge (Note 3,4)	Q_g		-	2.3	-	

Source-Drain Diode Ratings and Characteristics ($T_C=25\text{ }^\circ\text{C}$, unless otherwise noted)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Source current (DC)	I_S	Integral reverse diode in the MOSFET	-	-	5.5	A
Source current (Pulsed)	I_{SM}		-	-	22	A
Forward voltage	V_{SD}	$V_{GS} = 0\text{V}, I_{SD} = 5.5\text{A}$	-	-	1.4	V
Reverse recovery time (Note 3,4)	t_{rr}	$I_{SD} = 5.5\text{A}, V_{GS} = 0\text{V}$	-	270	-	ns
Reverse recovery charge (Note 3,4)	Q_{rr}	$dI_F/dt = 100\text{A}/\mu\text{s}$	-	1.9	-	μC

Note :

1. Repeated rating : Pulse width limited by safe operating area.
2. $L = 22\text{mH}, I_{AS} = 5.5\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$ Starting $T_J = 25^\circ\text{C}$
3. Pulse test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
4. Essentially independent of operating temperature typical characteristics.

Typical Electrical Characteristic

Fig. 1 Typical Output Characteristics

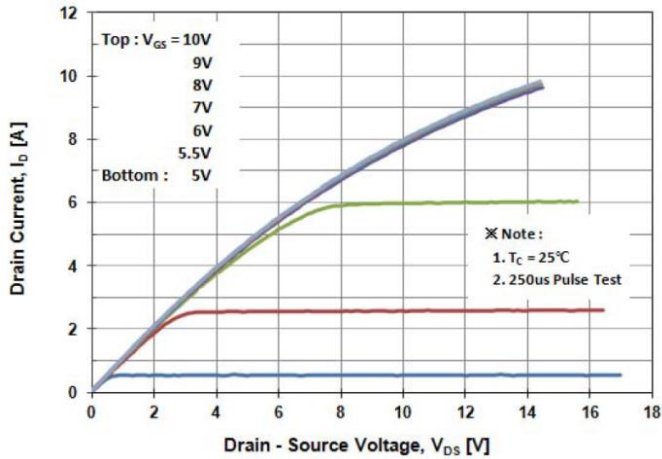


Fig. 3 On-Resistance Variation with Drain Current and Gate Voltage

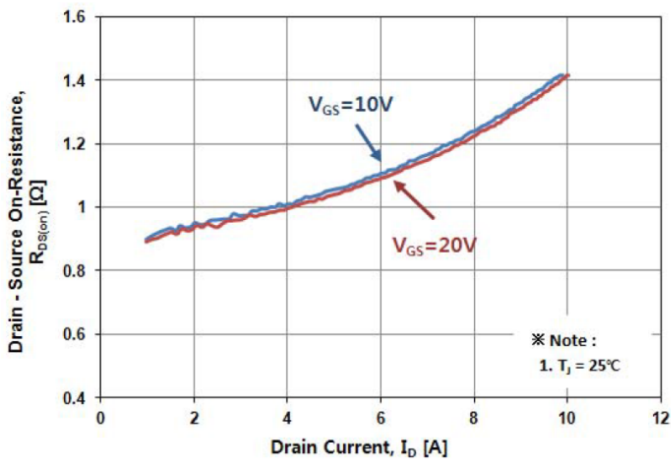


Fig. 5 Typical Capacitance Characteristics

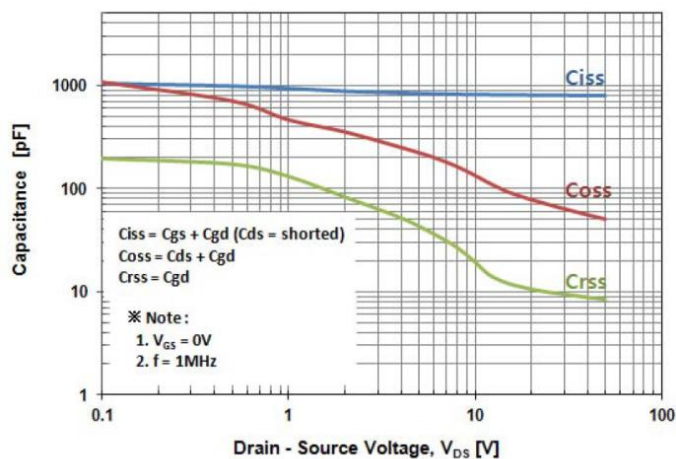


Fig. 2 Typical Transfer Characteristics

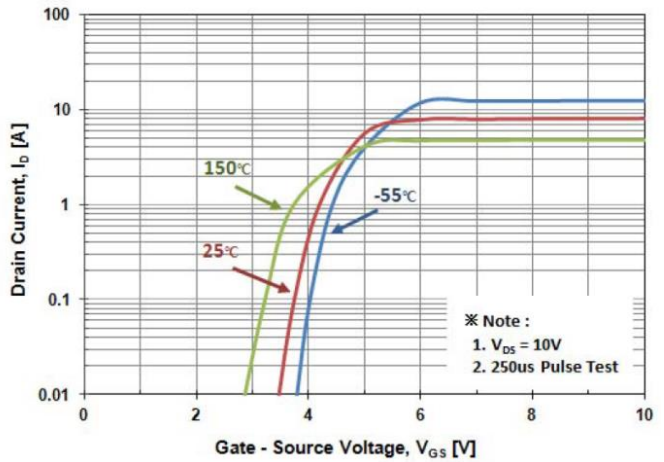


Fig. 4 Body Diode Forward Voltage Variation with Source Current

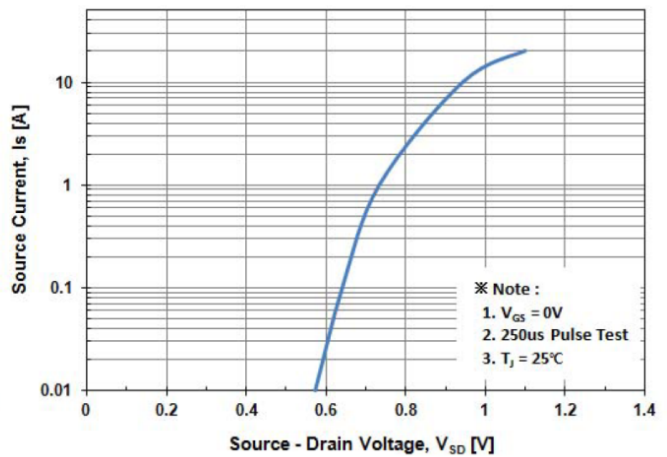


Fig. 6 Typical Total Gate Charge Characteristics

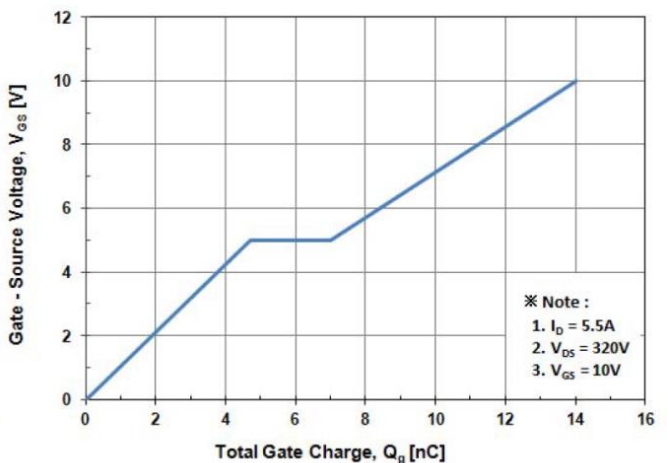


Fig. 7 Breakdown Voltage Variation vs. Temperature

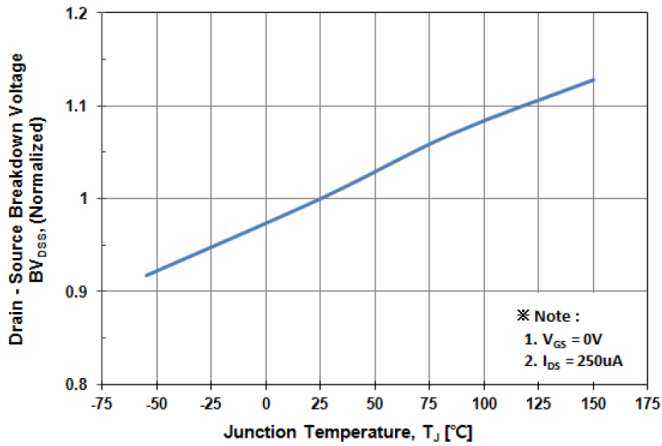


Fig. 8 On-Resistance Variation vs. Temperature

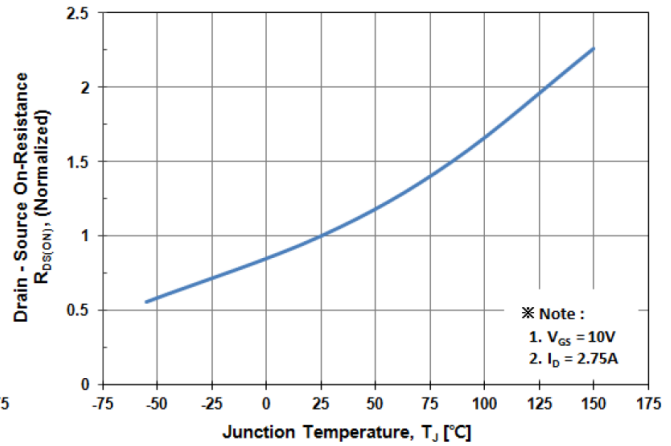


Fig. 9 Maximum Drain Current vs. Case Temperature

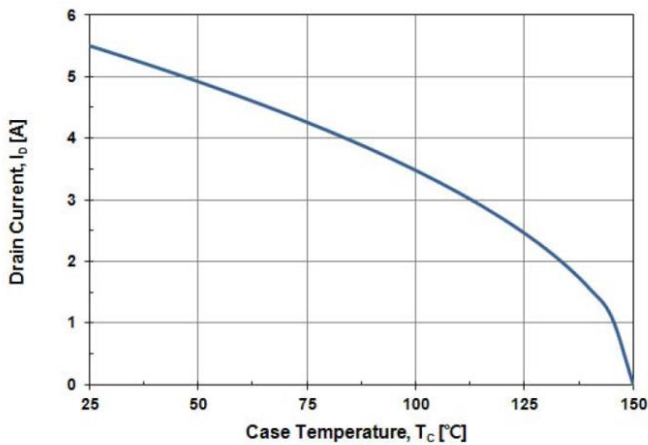


Fig. 10 Maximum Safe Operating Area

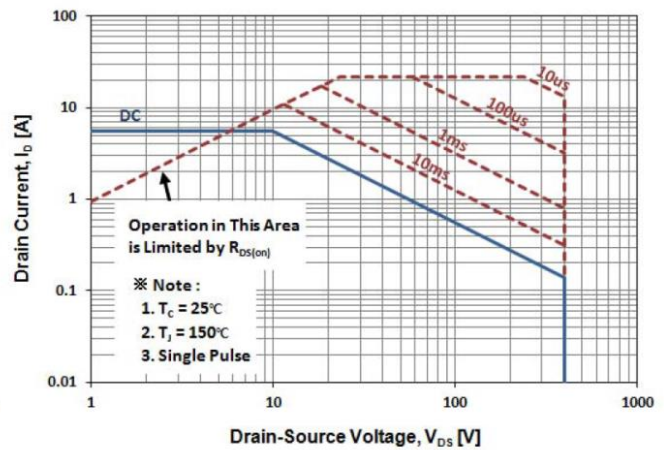


Fig. 11 Transient Thermal Impedance

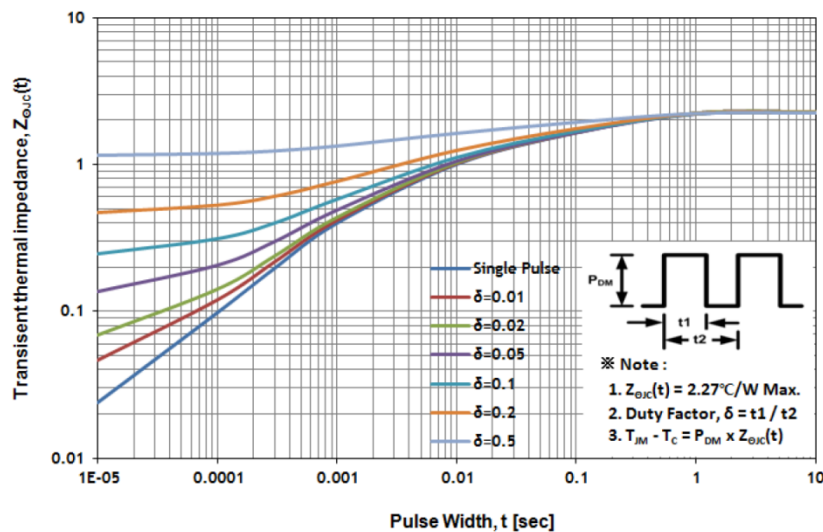


Fig. 12 Gate Charge Test Circuit & Waveform

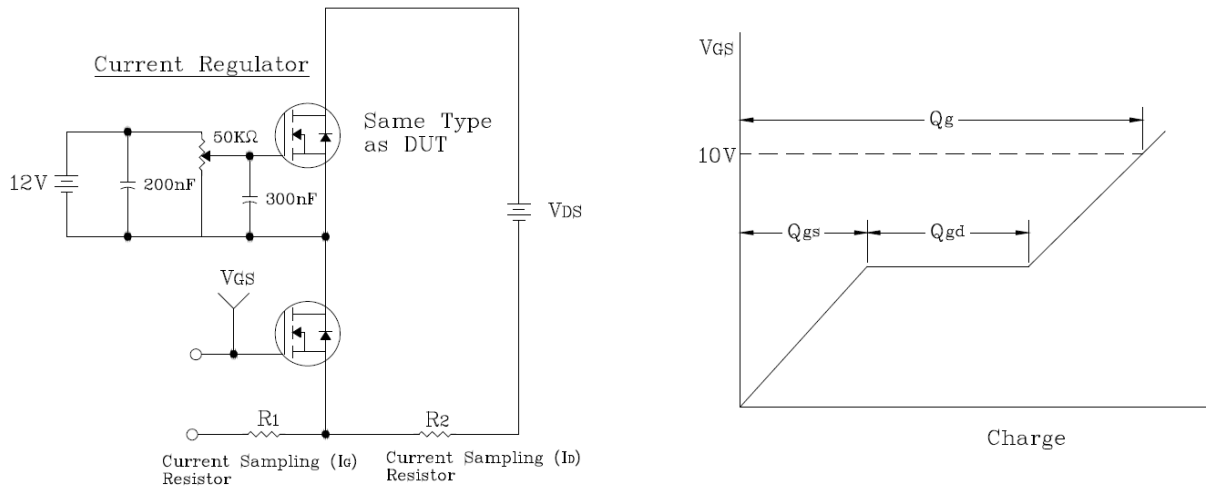


Fig. 13 Resistive Switching Test Circuit & Waveform

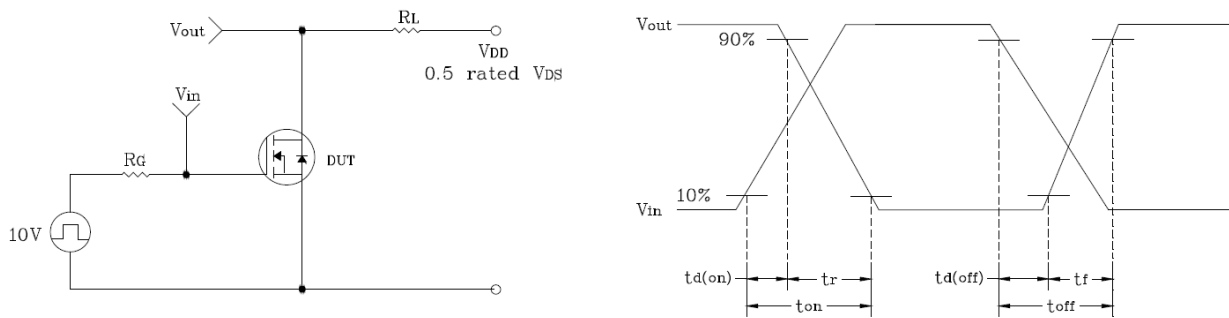


Fig. 14 E_{AS} Test Circuit & Waveform

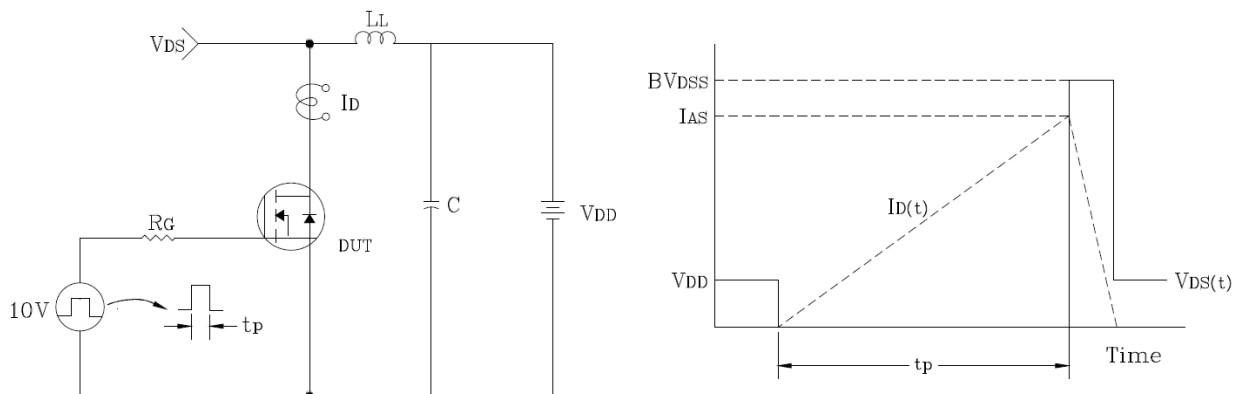
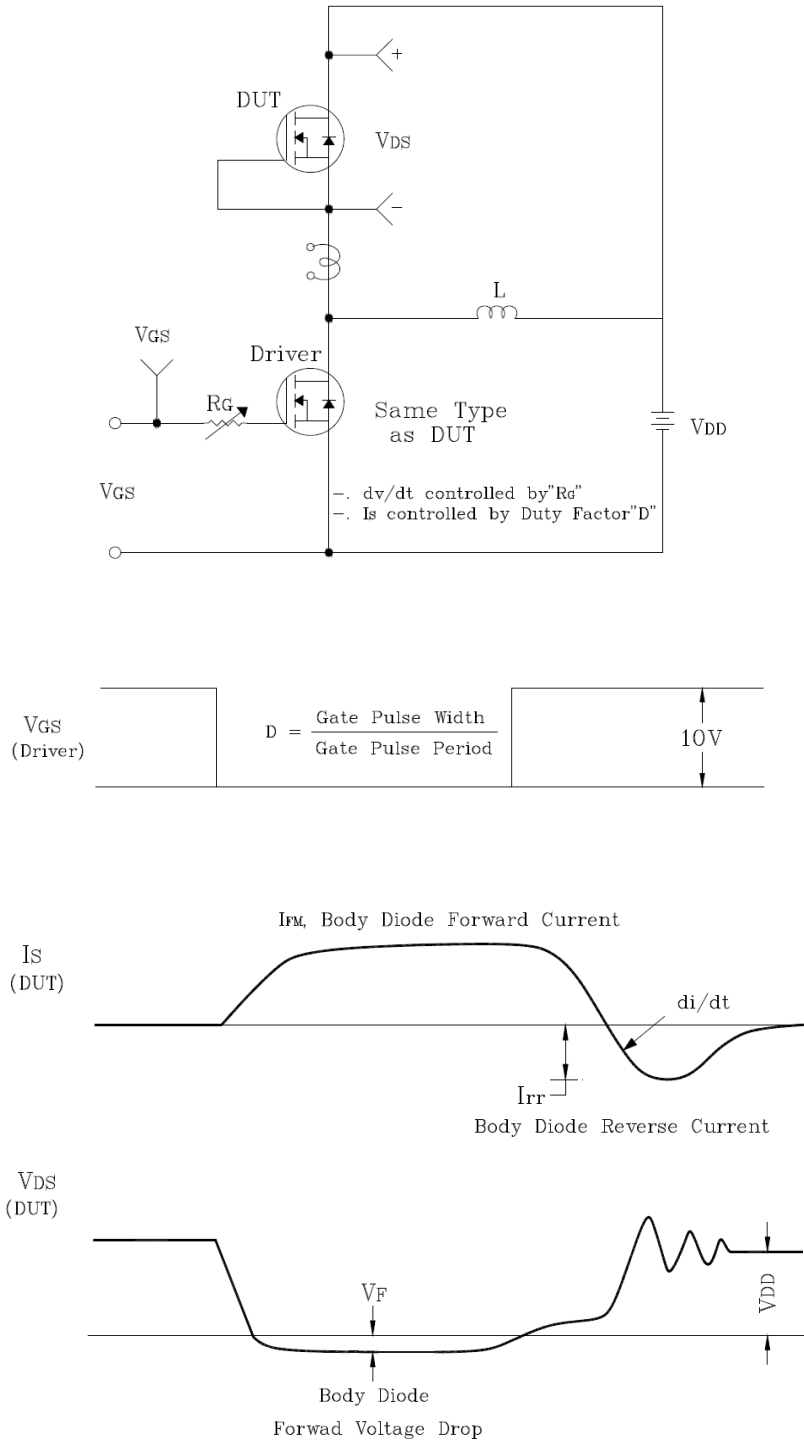


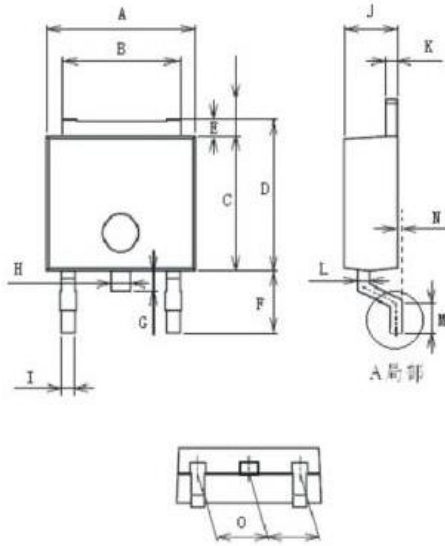
Fig. 15 Diode Reverse Recovery Time Test Circuit & Waveform





Package Dimensions

TO-252



Unit: mm

Item	Min	Max
A	6.40	6.70
B	5.20	5.40
C	6.00	6.30
D	6.55	6.85
E	0.45	0.60
F	3.07	3.35
G	0.85	1.05
H	0.75	0.95
I	0.55	0.75
J	2.20	2.40
K	0.43	0.58
L	0.43	0.58
M	0.90	1.10
N	0.90	1.10
O	2.20	2.40



Revision History

No	Date	Contents
0	2016-03-31	Initial Brief Datasheet Release



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